

FDA69N25 250V N-Channel MOSFET

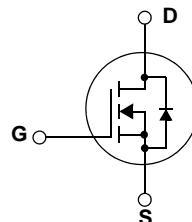
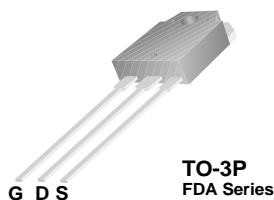
Features

- 69A, 250V, $R_{DS(on)} = 0.041\Omega$ @ $V_{GS} = 10\text{ V}$
- Low gate charge (typical 77 nC)
- Low Crss (typical 84pF)
- Fast switching
- Improved dv/dt capability

Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies, active power factor correction, electronic lamp ballast based on half bridge topology.



Absolute Maximum Ratings

Symbol	Parameter	FDA69N25	Units
V_{DSS}	Drain-Source Voltage	250	V
$V_{DS(\text{Avalanche})}$	Repetitive Avalanche Voltage (Note 1) (Note 2)	300	V
I_D	Drain Current - Continuous ($T_C = 25^\circ\text{C}$)	69	A
	- Continuous ($T_C = 100^\circ\text{C}$)	44.2	A
I_{DM}	Drain Current - Pulsed (Note 1)	276	A
V_{GSS}	Gate-Source Voltage	± 30	V
E_{AS}	Single Pulsed Avalanche Energy (Note 2)	1894	mJ
I_{AR}	Avalanche Current (Note 1)	69	A
E_{AR}	Repetitive Avalanche Energy (Note 1)	48	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	4.5	V/ns
P_D	Power Dissipation ($T_C = 25^\circ\text{C}$)	480	W
	- Derate above 25°C	3.84	W/ $^\circ\text{C}$
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
T_L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

Thermal Characteristics

Symbol	Parameter	FDA69N25	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.26	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	40	$^\circ\text{C/W}$

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDA69N25	FDA69N25	TO-3P	--	--	30

Electrical Characteristics

$T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units	
Off Characteristics							
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$	250	--	--	V	
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C	--	0.25	--	$\text{V}/^\circ\text{C}$	
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 250 \text{ V}$, $V_{\text{GS}} = 0 \text{ V}$	--	--	1	μA	
		$V_{\text{DS}} = 200 \text{ V}$, $T_C = 125^\circ\text{C}$	--	--	10	μA	
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{\text{GS}} = 30 \text{ V}$, $V_{\text{DS}} = 0 \text{ V}$	--	--	100	nA	
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{\text{GS}} = -30 \text{ V}$, $V_{\text{DS}} = 0 \text{ V}$	--	--	-100	nA	
On Characteristics							
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}$, $I_D = 250 \mu\text{A}$	3.0	--	5.0	V	
$R_{\text{DS(on)}}$	Static Drain-Source On-Resistance	$V_{\text{GS}} = 10 \text{ V}$, $I_D = 34.5 \text{ A}$	--	0.034	0.041	Ω	
g_{FS}	Forward Transconductance	$V_{\text{DS}} = 40 \text{ V}$, $I_D = 34.5 \text{ A}$	(Note 4)	--	25	--	S
Dynamic Characteristics							
C_{iss}	Input Capacitance	$V_{\text{DS}} = 25 \text{ V}$, $V_{\text{GS}} = 0 \text{ V}$, $f = 1.0 \text{ MHz}$	--	3570	4640	pF	
C_{oss}	Output Capacitance		--	750	980	pF	
C_{rss}	Reverse Transfer Capacitance		--	84	130	pF	
Switching Characteristics							
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}} = 125 \text{ V}$, $I_D = 69 \text{ A}$, $R_G = 25 \Omega$	--	95	200	ns	
t_r	Turn-On Rise Time		--	855	1720	ns	
$t_{\text{d(off)}}$	Turn-Off Delay Time		--	130	270	ns	
t_f	Turn-Off Fall Time		--	220	450	ns	
Q_g	Total Gate Charge	$V_{\text{DS}} = 200 \text{ V}$, $I_D = 69 \text{ A}$, $V_{\text{GS}} = 10 \text{ V}$	--	77	100	nC	
Q_{gs}	Gate-Source Charge		--	24	--	nC	
Q_{gd}	Gate-Drain Charge		--	37	--	nC	
Drain-Source Diode Characteristics and Maximum Ratings							
I_S	Maximum Continuous Drain-Source Diode Forward Current	--	--	34	--	A	
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current	--	--	136	--	A	
V_{SD}	Drain-Source Diode Forward Voltage	$V_{\text{GS}} = 0 \text{ V}$, $I_S = 69 \text{ A}$	--	--	1.4	V	
t_{rr}	Reverse Recovery Time	$V_{\text{GS}} = 0 \text{ V}$, $I_S = 69 \text{ A}$, $dI_F/dt = 100 \text{ A}/\mu\text{s}$	(Note 4)	--	210	--	ns
Q_{rr}	Reverse Recovery Charge	--	--	5.7	--	μC	

NOTES:

1. Repetitive Rating : Pulse width limited by maximum junction temperature

2. $L = 0.64\text{mH}$, $I_{AS} = 69\text{A}$, $V_{DD} = 50\text{V}$, $R_G = 25 \Omega$, Starting $T_J = 25^\circ\text{C}$

3. $I_{SD} \leq 69\text{A}$, $dI/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq \text{BV}_{\text{DSS}}$, Starting $T_J = 25^\circ\text{C}$

4. Pulse Test : Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$

5. Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. On-Region Characteristics

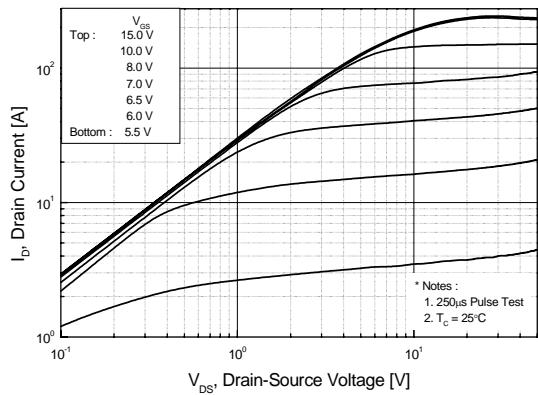


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

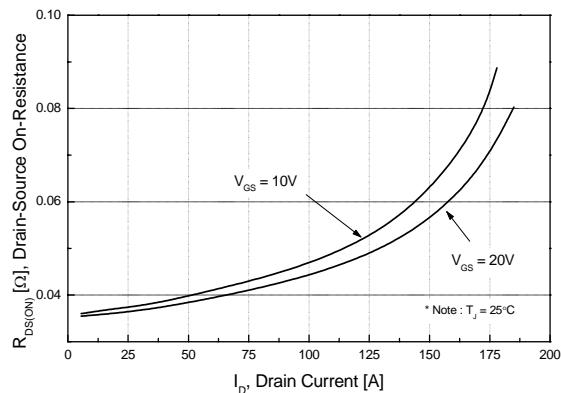


Figure 2. Transfer Characteristics

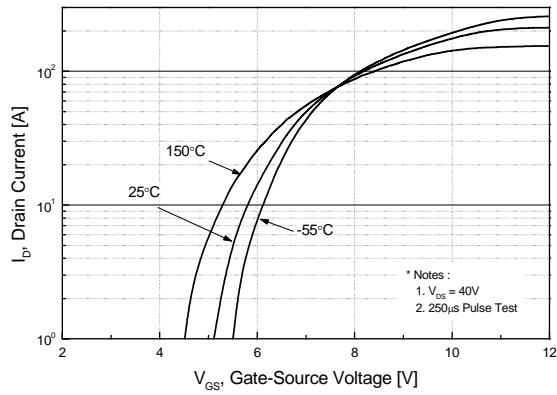


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

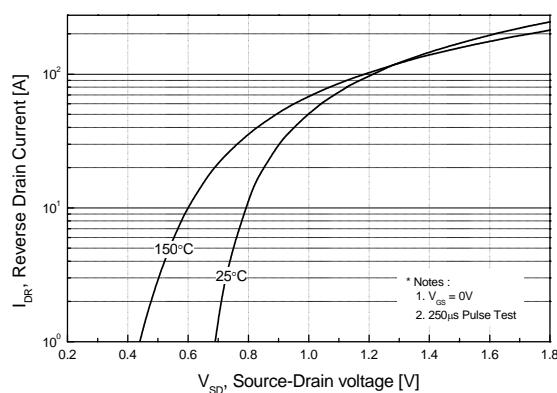


Figure 5. Capacitance Characteristics

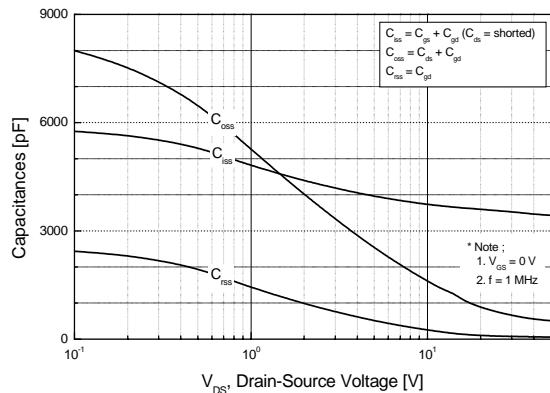
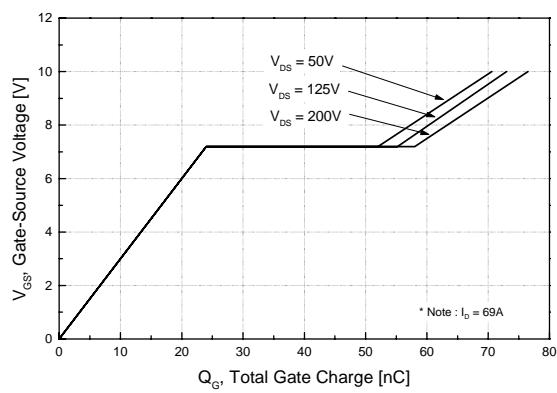


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

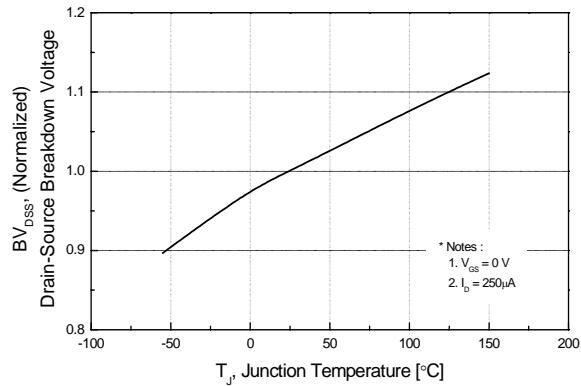


Figure 8. On-Resistance Variation vs. Temperature

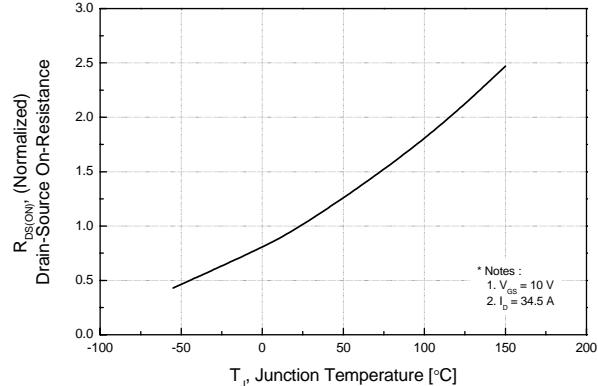


Figure 9. Maximum Safe Operating Area

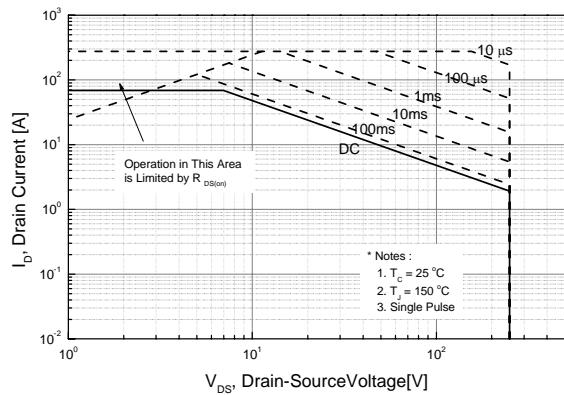


Figure 10. Maximum Drain Current vs. Case Temperature

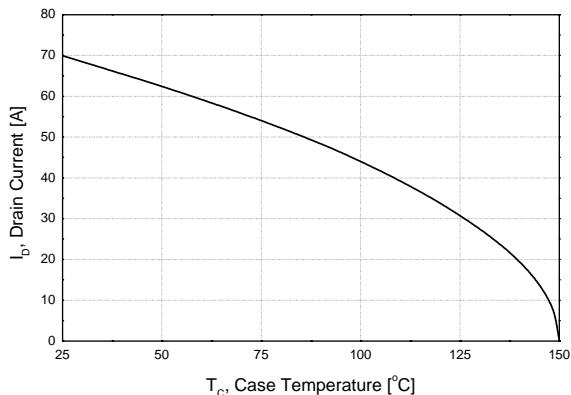
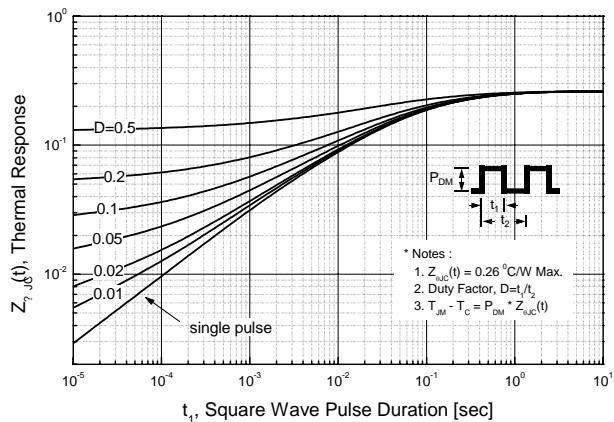


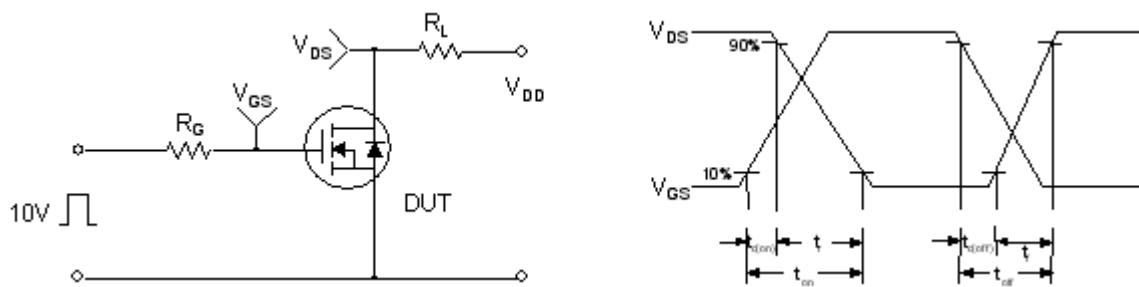
Figure 11. Transient Thermal Response Curve



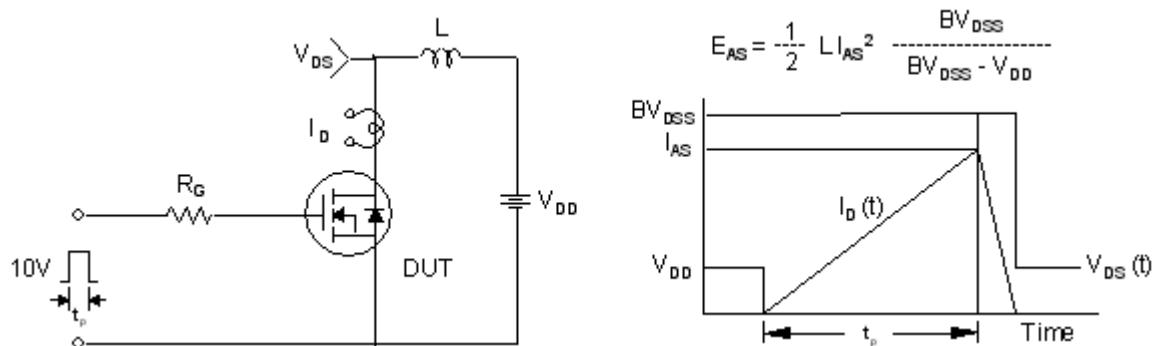
Gate Charge Test Circuit & Waveform



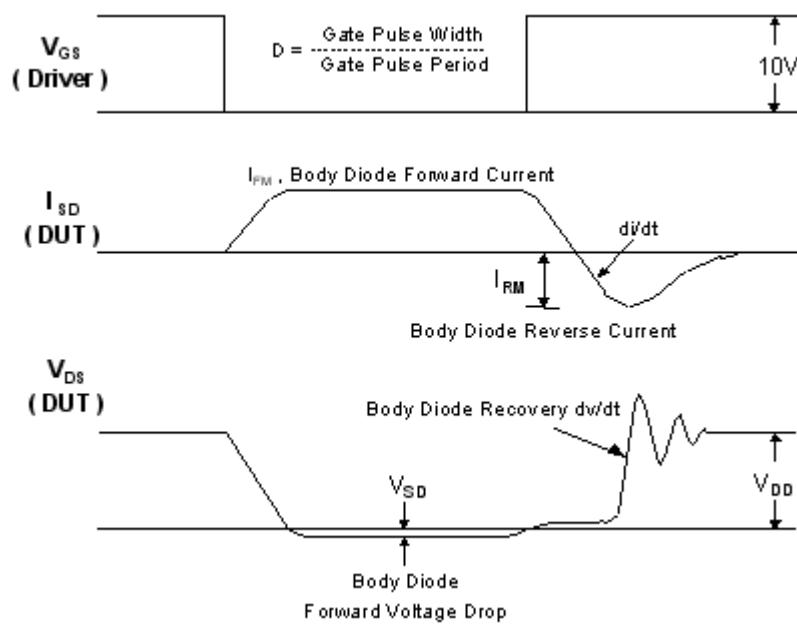
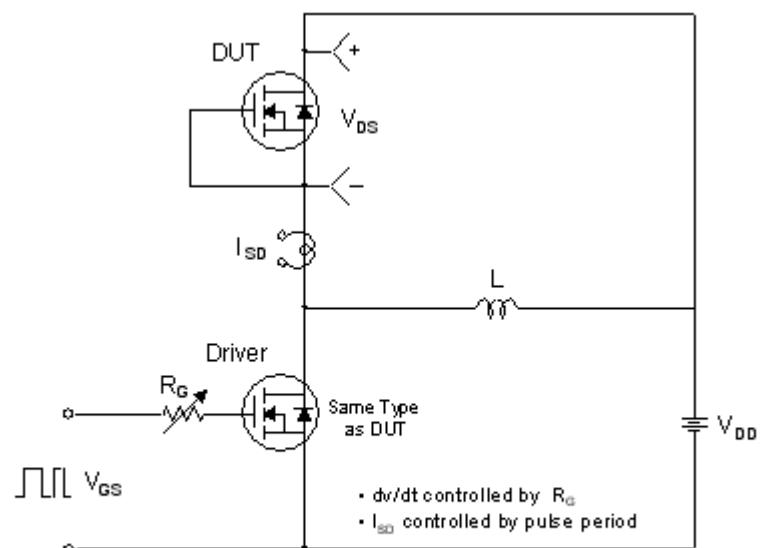
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

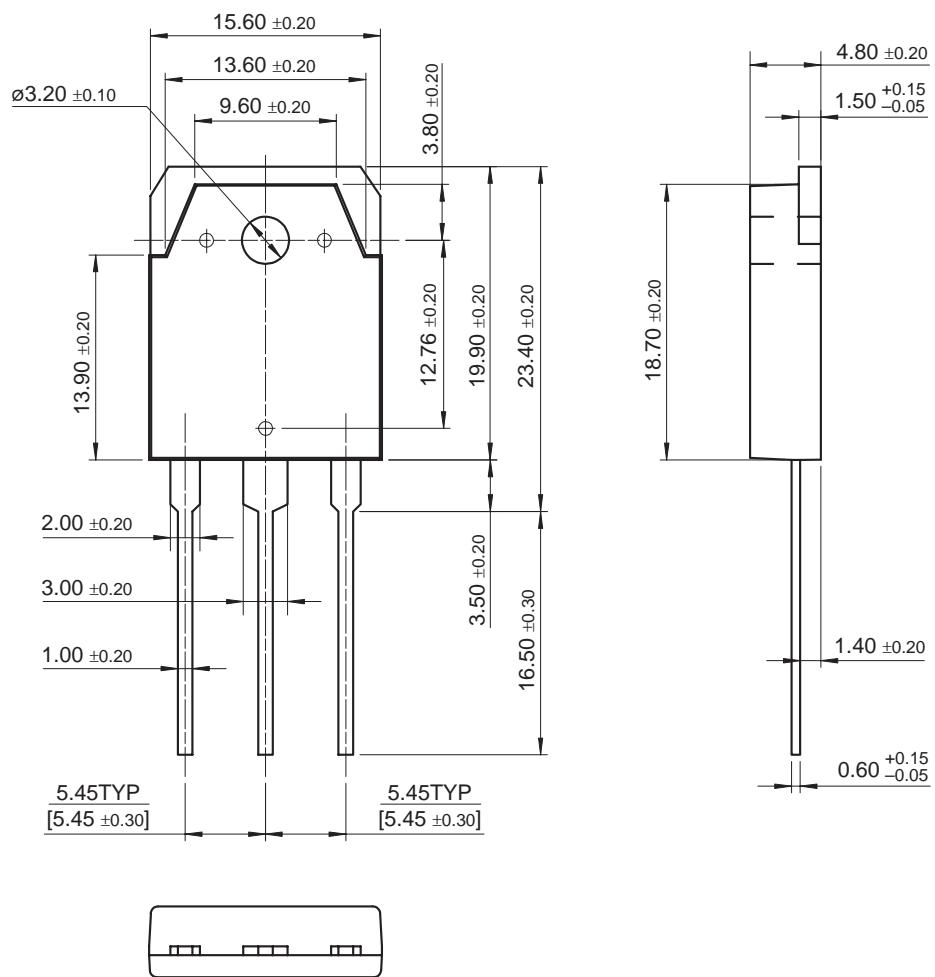


Peak Diode Recovery dv/dt Test Circuit & Waveforms



Mechanical Dimensions

TO-3P



Dimensions in Millimeters

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Rev. I19